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Title: TESTING MULTIPLE LEVELS IN
INTEGRATED CIRCUIT TECHNOLOGY
DEVELOPMENT
Inventors: Paul J. Steffan, et al.

Docket No.: H0778

Contact: Mikio Ishimaru (408) 738-0592

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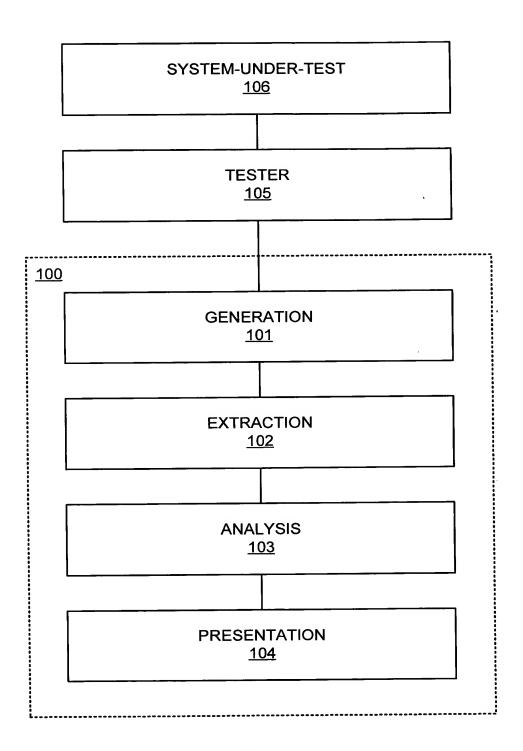


FIG. 1

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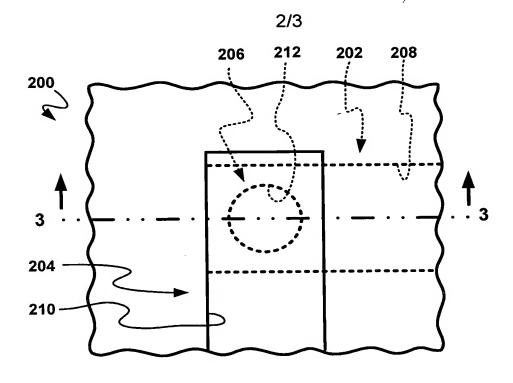


FIG. 2

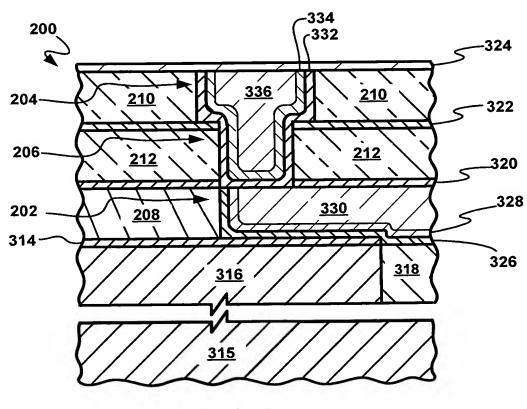
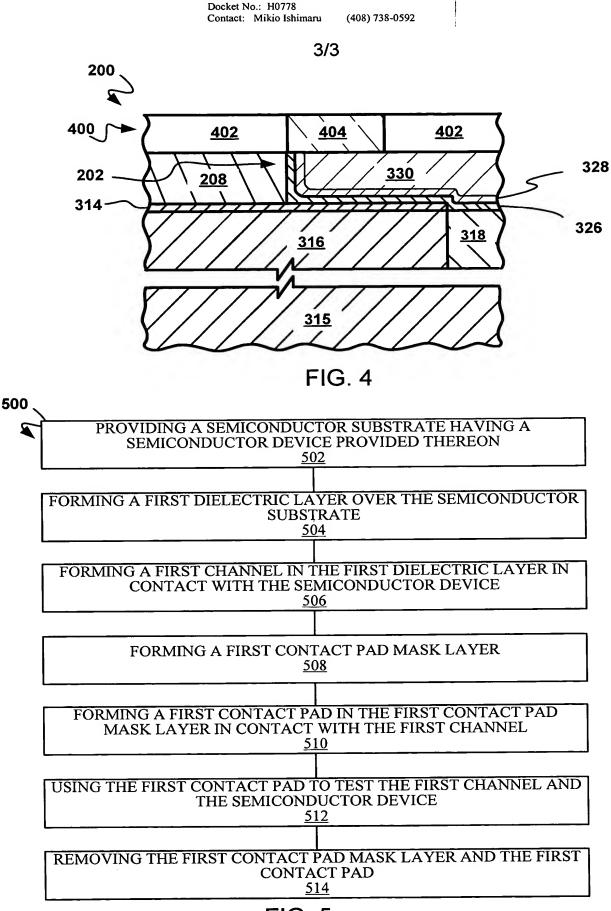


FIG. 3



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TESTING MULTIPLE LEVELS IN INTEGRATED CIRCUIT TECHNOLOGY

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FIG. 5